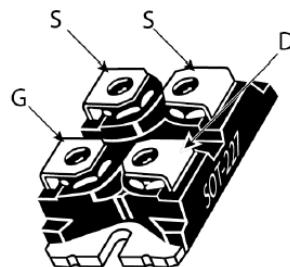


Description

Silicon Carbide (SiC) MOSFET use a completely new technology that provide superior switching performance and higher reliability compared to Silicon. In addition, the low ON resistance and compact chip size ensure low capacitance and gate charge. Consequently, system benefits include highest efficiency, faster operating frequency, increased power density, reduced EMI, and reduced system size.

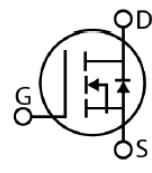
Features

- High Speed Switching with Low Capacitances
- High Blocking Voltage with Low RDS(on)
- Fast and reliable body diode
- Easy to parallel and simple to drive
- Superior avalanche ruggedness
- ROHS Compliant, Halogen free
- Isolated voltage to 2500 V



Application

- PV inverter, converter, and industrial motor drives
- Smart grid transmission and distribution
- Induction heating and welding
- Power supply and distribution
- H/EV powertrain and EV charger



G—Gate
D—Drain
S—Source

Ordering Information

Part Number	Marking	Package	Packaging
A2G100N1200MDS	A2G100N1200MDS	SOT227	Box

Absolute Maximum Ratings(Tc=25 °C)

Symbol	Parameter	Value	Unit
V _{DS}	Drain-Source Voltage	1200	V
I _D	Drain Current(continuous)at Tc=25°C	115	A
I _D	Drain Current(continuous)at Tc=100°C	85	A
I _{DM}	Drain Current (pulsed)	280	A
V _{GS}	Gate-Source Voltage	-10/+25	V
P _D	Power Dissipation T _C = 25°C	428	W
T _J , T _{stg}	Junction and Storage Temperature Range	-55 to +175	°C

Electrical Characteristics(T_J = 25 °C unless otherwise specified)
Typical Performance-Static

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
BV _{DS}	Drain-source Breakdown Voltage	I _D =100uA, V _{GS} =0V	1200			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =1200V, V _{GS} =0V, T _J =25°C		5	100	uA
I _{GSS}	Gate-body Leakage Current	V _{DS} =0V ; V _{GS} =-10 to 20V		10	100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D =22mA	2	3	4	V
V _{GSon}	Recommended turn-on Voltage	Static		20		V
V _{Gsoff}	Recommended turn-off Voltage			-5		V
R _{DS(on)}	Static Drain-source On Resistance	V _{GS} =20V, I _D =50A		16	22	mΩ
		V _{GS} =20V, I _D =50A T _J =175°C		32		mΩ

Typical Performance-Dynamic

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input Capacitance	$V_{DS}=1000V, f=1MHz$, $V_{AC}=25mV$		6378		pF
C_{oss}	Output Capacitance			245		pF
C_{rss}	Reverse Transfer Capacitance			15		pF
g_{fs}	Transconductance	$V_{DS}=20V, I_D=50A$		51		S
E_{oss}	Coss Stored Energy	$V_{DS}=1000V, f=1MHz$		141		μJ
E_{ON}	Turn-On Energy (Body Diode)	$V_{DS}=800V, V_{GS}=-5/20V$, $I_D=50A, L=68\mu H$		2.60		mJ
E_{OFF}	Turn-Off Energy (Body Diode)			0.73		mJ
Q_g	Total Gate Charge	$V_{DS}=800V, V_{GS}=-5V/20V$, $I_D = 50 A$		238		nC
Q_{gs}	Gate-source Charge			76.7		nC
Q_{gd}	Gate-Drain Charge			78.3		nC
$R_{G(int)}$	Internal Gate Resistance	$f=1MHz, V_{AC}=25mV$		3.5		Ω
$t_{d(on)}$	Turn-on Delay Time	$V_{DS}=800V, V_{GS}=-5V/20V$, $I_D = 50A, L=68 \mu H$		42		ns
t_r	Rise Time			34		ns
$t_{d(off)}$	Turn-off Delay Time			71		ns
t_f	Fall Time			13		ns
E_{AS}	Avalanche energy, single Pulse	$V_{DS}=150V, I_D = 30A$		3500		mJ

Typical Performance-Reverse Diode($T_J = 25^\circ C$ unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V_{FSD}	Forward Voltage	$V_{GS}=0V, I_F=37.5A, T_J=25^\circ C$		4.6	6	V
		$V_{GS}=0V, I_F=37.5A, T_J=150^\circ C$		4.2	6	V
I_S	Continuous Diode Forward Current	$V_{GS}=0V, T_C=25^\circ C$		110		A
t_{rr}	Reverse Recovery Time	$V_{GS}=-5 V, I_F=50 A$,		98		nS
Q_{rr}	Reverse Recovery Charge			613		nC
I_{rrm}	Peak Reverse Recovery Current			18		A

Thermal Characteristics

Symbol	Parameter	Value.	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.35	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	40	$^\circ C/W$
VIISOLATION	Any terminal to case, t=1 minute	2500	V

The values are based on the junction-to case thermal impedance which is measured with the device mounted to a large heat sink assuming maximum junction temperature of $T_j(max)=175^\circ C$

Electrical Characteristics

Fig1. Output characteristics ($T_J = 25^\circ\text{C}$)

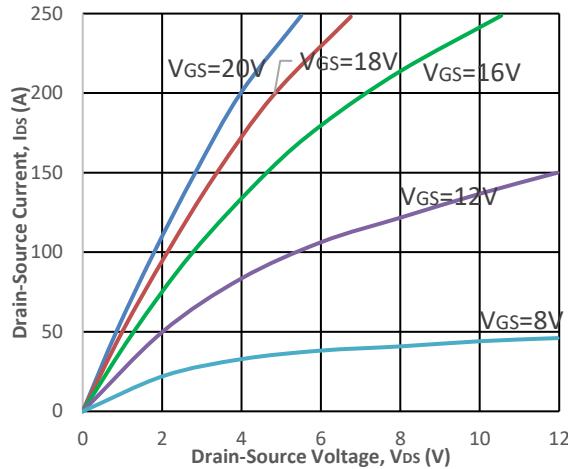


Fig2. Output characteristics ($T_J = 150^\circ\text{C}$)

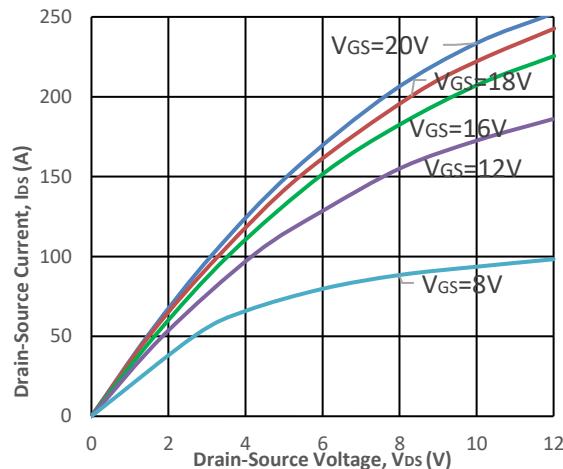


Fig3. Normalized On-Resistance vs. Temperature

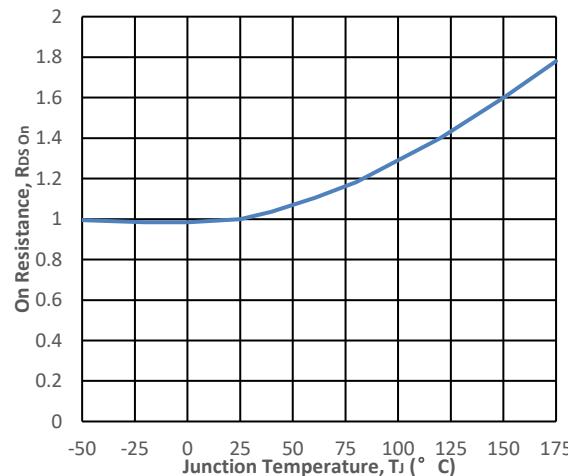


Fig4. On-Resistance vs. Temperature

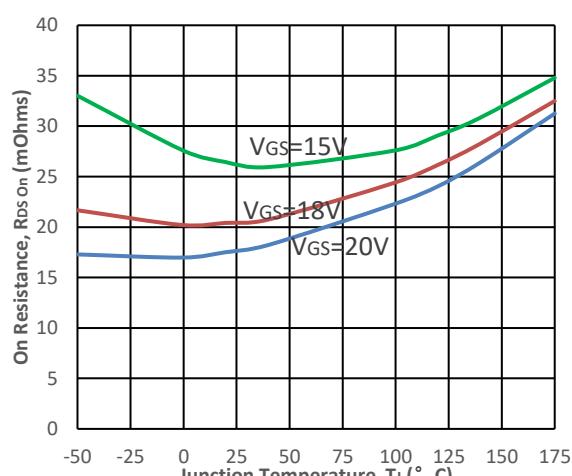


Fig5. Transfer Characteristic

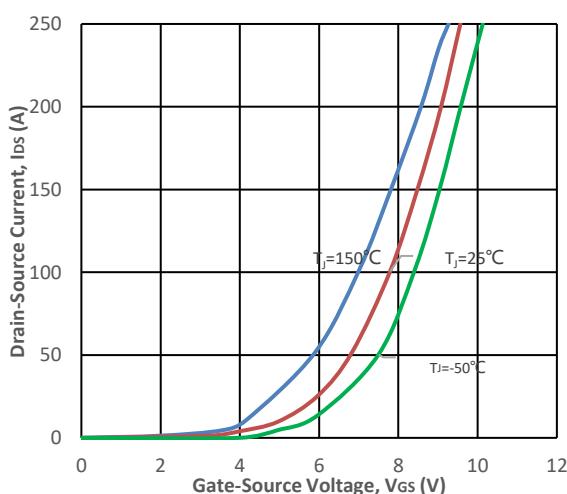


Fig6. Body Diode Characteristic at 25°C

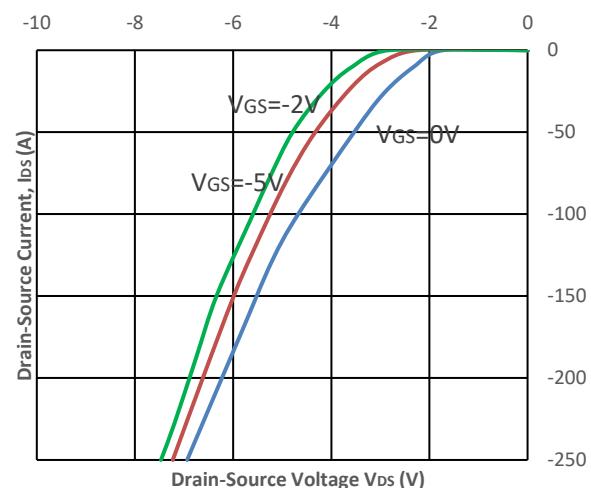


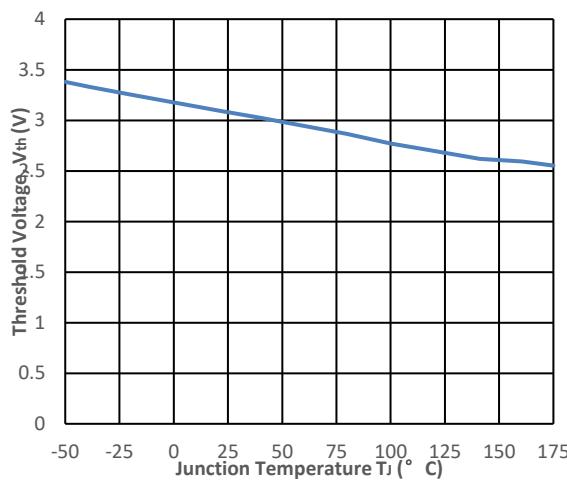
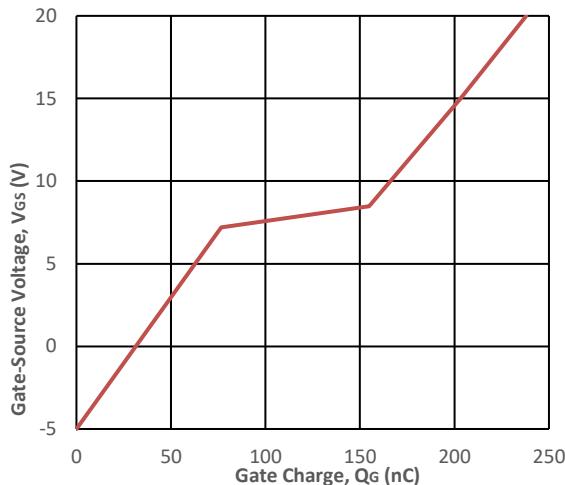
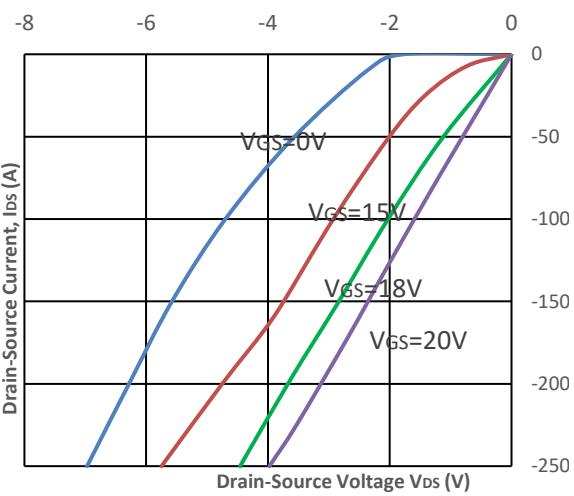
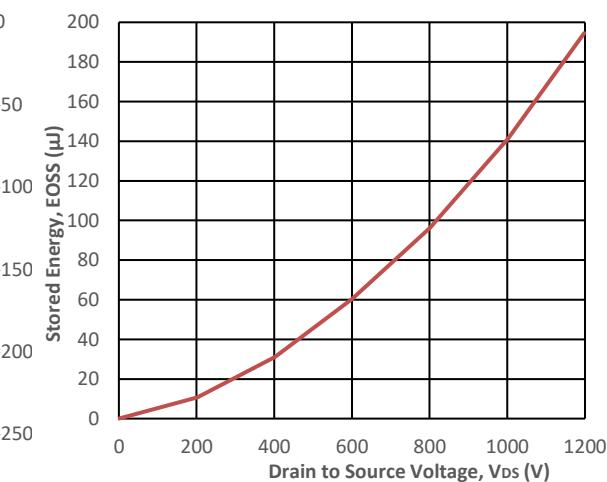
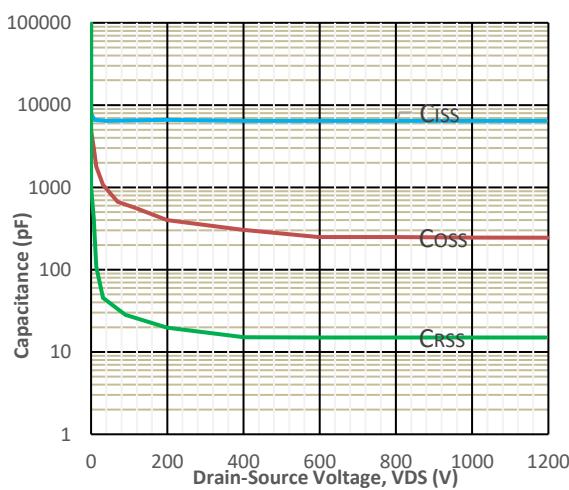
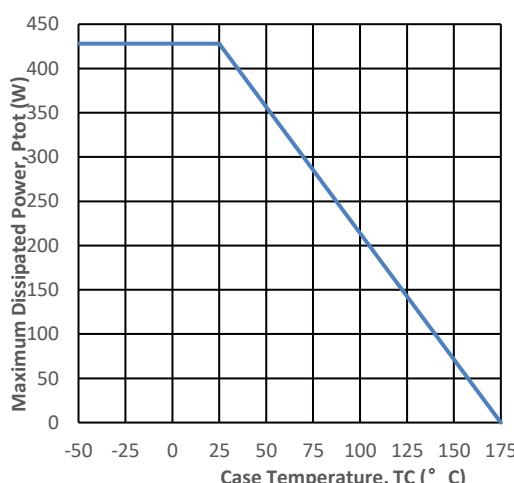
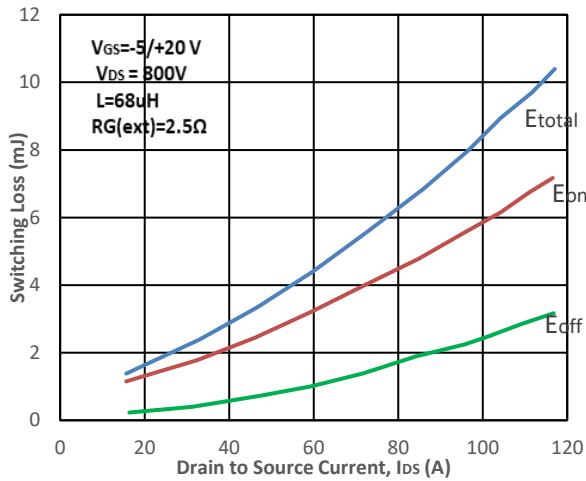
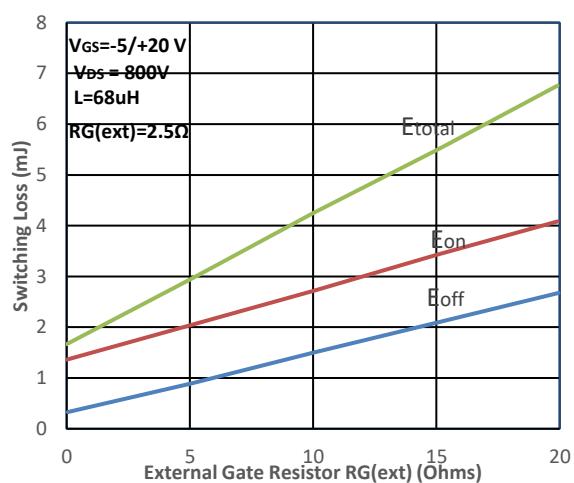
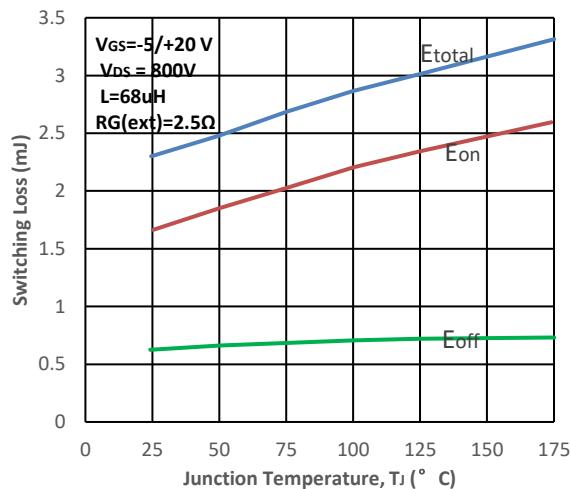
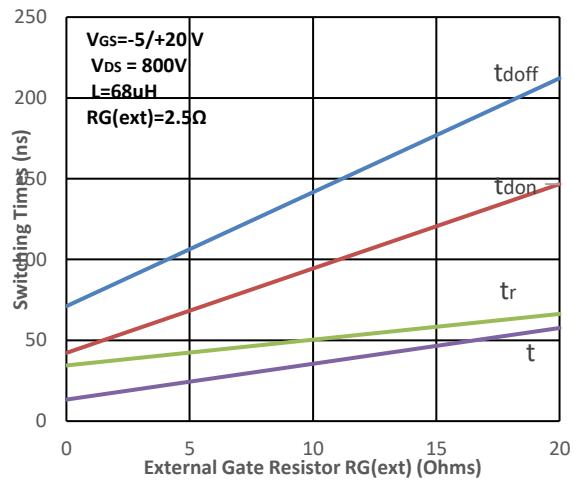
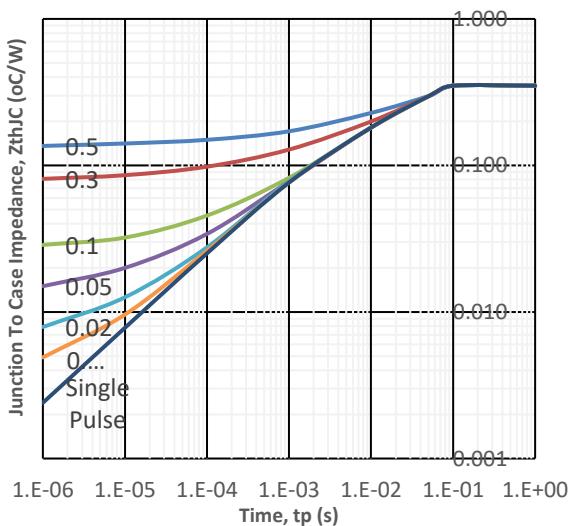
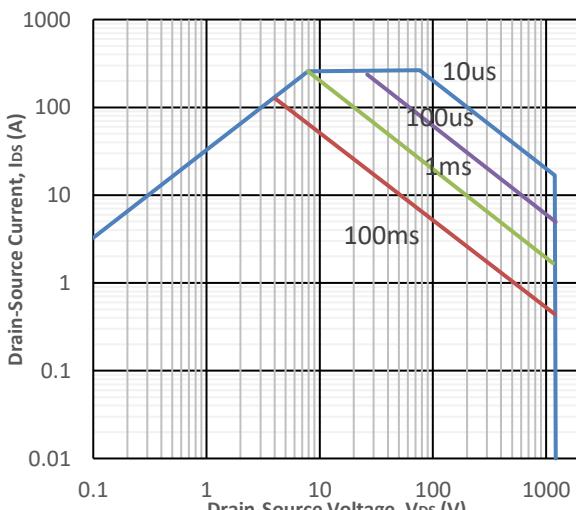
Fig7.Threshold Voltage vs. Temperature

Fig8. Gate Charge Characteristics

Fig9. 3rd Quadrant Characteristic at 25 °C

Fig10. Output Capacitor Stored Energy

Fig11. Capacitances vs. Drain-Source

Fig12. Max Power Dissipation Derating Vs Tc


Fig13. Switching Energy vs. Drain Current

Fig14. Switching Energy vs. RG(ext)

Fig15. Switching Energy vs. Temperature

Fig16. Switching Times vs. RG(ext)

Fig17. Transient Thermal Impedance

Fig18. Safe Operating Area


Package Drawing and Dimensions (UNIT: mm)

